

Notice of References Cited		Application/Control No. 10/561,830	Applicant(s)/Patent Under Reexamination HAYASHI ET AL.	
		Examiner ANCA EOFF	Art Unit 1795	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0009667	01-2002	Nishimura et al.	430/270.1
*	B	US-2004/0058269	03-2004	Hada et al.	430/270.1
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	L	US-			
	M	US-			

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	N	WO 03/048863	06-2003		Hada, H. et al.	
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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